
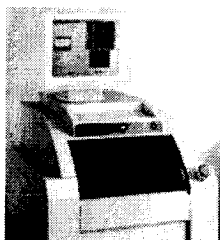


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MicroXR GXR/C Microbeam X-ray Fluorescence System

Equipped with monochromator optical collimation, the MicroXR GXR/C model precisely measures tin, palladium and silver structures as small as 25 μm , and gold and nickel structures as small as 40 μm .

Product Detail

MicroXR benchtop platform is a configurable microbeam XRF film thickness and composition measuring tool. This platform includes several X-ray beam and detection options for application flexibility, and provides unparalleled performance in accuracy, precision and reproducibility.

- Mechanical or optical X-ray beam collimation options
- Proportional counter, PIN diode, SDD or Si(Li) X-ray detector options
- Servo driven x-y-z stage with linear encoder option for accurate sample positioning
- Measurement method in accordance with ASTM B 568/ISO3497

Application Performance

The MicroXR platform employs X-ray fluorescence technology in its electronics and software. Application performance specifications ensure that your microbeam XRF system is designed for your specific application and operational purposes:

- Algorithms tools using empirical and fundamental parameters, non-standard and standard-corrected
- Alloy analysis up to a total of 30 elements
- Thickness and composition on one to five deposition layers and one substrate layer simultaneously, to a total of 30 elements per application
- Relative mode calibration for measurement on recessed areas (focus independent)
- Absorption mode
- Linear excitation mode
- Immersion coating mode
- Density and base correction
- Electroless Ni thickness and composition analysis (optional)

Measurement Performance

The MicroXR platform is designed for unsurpassed accuracy and versatility, including several features to tailor the instrument to specific measurements:

- Application and standards library
- Automated programmable stage measurement
- Automatic beam alignment
- Multiplexed graphical and video signal for single screen operation
- Point-and-shoot sample positioning
- Computer-generated reticle with beam size indicator
- Programmable icons with operator interface designer
- Two- and three-dimensional mapping software
- Full statistics package
- Part number management system with optional bar code reader

Purchase Details

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Literature Request

Postal Mail:

- [MicroXR Benchtop Platform Specification Sheet](#)
- [MicroXR Microbeam XRF Brochure](#)